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Application/Control No.	Applicant(s)/Patent under Reexamination	
10/792,292	FUJII ET AL.	
Examiner	Art Unit	
Adrian L. Kennedy	2121	

SEARCHED			
Class	Subclass	Date	Examiner
700	28	2/18/2007	AK
700	50	2/18/2007	AK
706	1	2/18/2007	AK
706	23	2/18/2007	AK
706	19	2/18/2007	AK
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INTERFERENCE SEARCHED			
Class	Subclass	Date	Examiner
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SEARCH NO (INCLUDING SEARCH)
	DATE	EXMR
EAST Updated	2/17/2007	AK
IEEE Search	2/17/2007	AK
East Updated	2/18/2007	AK
Google Scholar	2/18/2007	AK
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